

EECS 42 Intro, Digital Electronics, Fall 2003 Lecture 26: 12/04/03 A.R. Neureuther  
Version Date 11/30/03

## Review for the Final Exam

**Likely 7 Problems** \* Possible Bonus = 2/3 best +1/3 worst  
Midterm Bonus = 2/3 best +1/3 worst

- Transients\*
- Logic Functions and Timing Diagrams
- Circuit Analysis with dependent Sources
- Op-Amps\*
- Load Line and Static Analysis of Logic Gates
- CMOS Logic Functions, Delay, Latches
- Diode Circuit Analysis, Voltage Controlled R

See Web Site under Exams for Coverage, Review Sessions and Office Hours  
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## Lecture 7 PULSE: Output is Rising exponential then Falling exponential

Example: Switch rises at  $t=0$ , falls at  $t=0.1, 1$  or  $10\mu\text{sec}$  (Do  $1\mu\text{sec}$  case)

Now starting at  $1\mu\text{sec}$  we are discharging the capacitor so the form is a falling exponential with initial value  $3.16\text{V}$ :

What is equation?

Solution: for  $RC = 1\mu\text{sec}$ : during the first rise  $V$  obeys:

$$V = 5[1 - e^{-\frac{t}{10^{-6}}}]$$

Thus at  $t = 1\mu\text{sec}$ , rising voltage reaches

$$5[1 - e^{-1}] = 3.16\text{V}$$

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## How to Combine Gate to Produce a Desired Logic Function? (More basic Logical Synthesis)

Example:

A	B	C	F
0	0	0	0
0	0	1	1
0	1	0	0
0	1	1	0
1	0	0	0
1	0	1	0
1	1	0	1
1	1	1	0

$$F = \bar{A} B C + A B \bar{C}$$

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## Logical Synthesis Guided by DeMorgan's Theorem

DeMorgan's Theorem :

$$A + B + C = \overline{[\bar{A} \bar{B} \bar{C}]} \quad \text{or} \quad \bar{A} + \bar{B} + \bar{C} = \overline{[A B C]}$$

Example of Using DeMorgan's Theorem:

$$F = A \cdot B + C \cdot D \cdot E = \overline{[\bar{A} \bar{B} \bar{C} D E]}$$

Thus any sum of products expression can be immediately synthesized from NAND gates alone

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## TIMING DIAGRAMS

Show transitions of variables vs time

Note - becomes valid one gate delay after B switches

Note that - becomes valid two gate delays after B&C switch, because the invert function takes one delay and the NAND function a second.

No change at  $t = 3\tau$

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## Lecture 19 Feedback Can Provide Memory

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### EXAMPLE WITH BOTH SPECIAL CASES

**Lecture 8**

$I_1 - \frac{V_a}{R_1} - \frac{V_a}{R_2 + R_3} - \frac{V_a + V_2}{R_4} = 0$

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### The 4 Basic Linear Dependent Sources

**Lecture 13**

Constant of proportionality    Parameter being sensed

Output

Voltage-controlled voltage source ...  $V = A_v V_{cd}$   
 Current-controlled voltage source ...  $V = R_m I_c$   
 Current-controlled current source ...  $I = A_i I_c$   
 Voltage-controlled current source ...  $I = G_m V_{cd}$

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### EXAMPLE CIRCUIT: INCREASED OUTPUT RESISTANCE

Add resistor  $R_E$

The input has been assumed to be shorted

Analysis: apply  $i_{TEST}$  and evaluate  $v_{TEST}$

Unknowns:  $i_{TEST}$ ,  $v_{TEST}$ ,  $v_{IN}$ ,  $v_E$

Need 3 equations to find the ratio of  $i_{TEST} / v_{TEST}$

$v_{IN} = -v_E$  and is **not zero!**  
 KCL at  $v_E$   
 KVL at  $v_{OUT}$

Intuitive Explanation:  $G_m V_{IN}$  burps current which has to also go through  $R_O$ . This raises  $v_{TEST}$  and the output impedance  $v_{TEST} / i_{TEST}$

Try a bag. It is even easier

Finish this in the homework

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### CASCADE OP-AMP CIRCUITS

How do you get started on finding  $V_0$ ?

Hint: Identify Stages  
 Hint:  $I_{IN}$  does not affect  $V_0$

See the further examples of op-amp circuits in the reader

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### Saturation Current NMOS Model

**Lecture 17**

Current  $I_{OUT}$  only flows when  $V_{IN}$  is larger than the threshold value  $V_{TD}$  and the current is proportional to  $V_{OUT}$  up to  $V_{OUT-SAT-D}$  where it reaches the saturation current

$$I_{OUT-SAT-D} = k_D (V_{IN} - V_{TD}) V_{OUT-SAT-D}$$

Note that we have added an extra parameter to distinguish between threshold ( $V_{TD}$ ) and saturation ( $V_{OUT-SAT-D}$ ).

Example:  
 $k_D = 25 \mu A/V^2$  Use these values in the homework.  
 $V_{TD} = 1V$   
 $V_{OUT-SAT-D} = 1V$

$I_{OUT-SAT-PD} = 25 \frac{\mu A^2}{V^2} (3V - 1V)V = 50 \mu A$

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### Composite Current Plot for the 42PD Circuit with 200kΩ Load to Ground

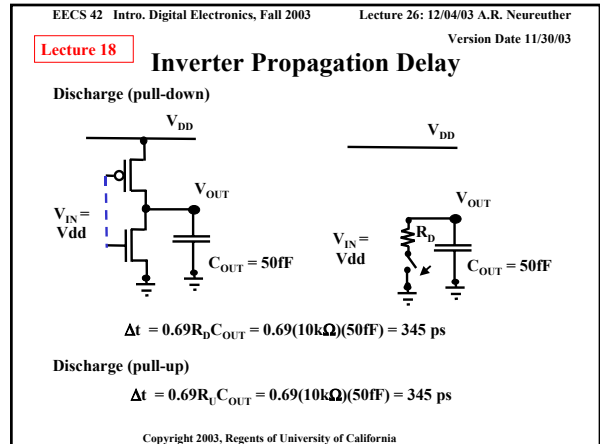
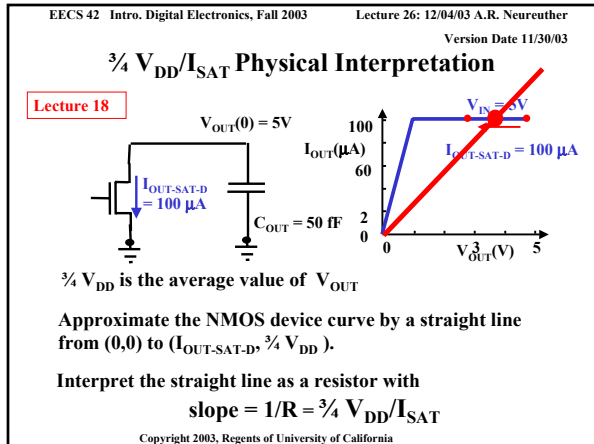
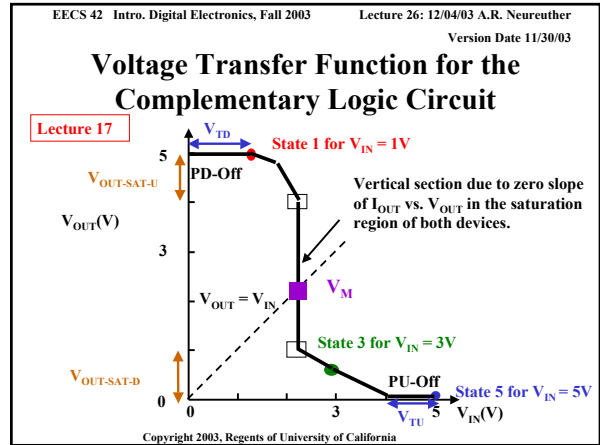
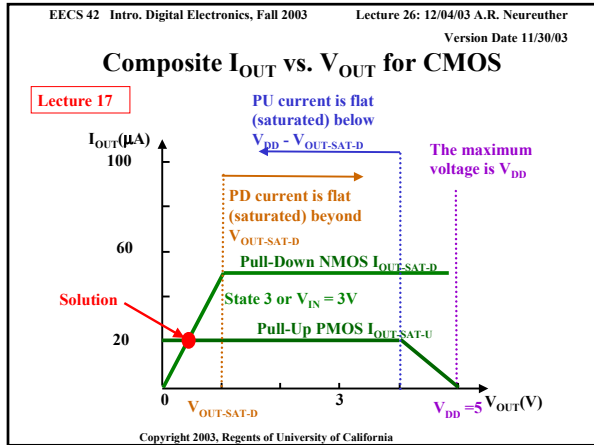
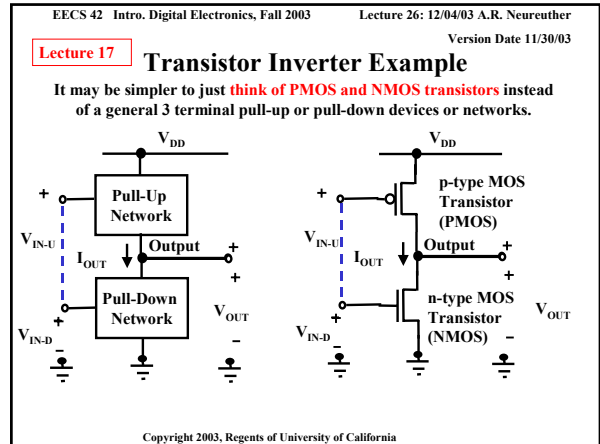
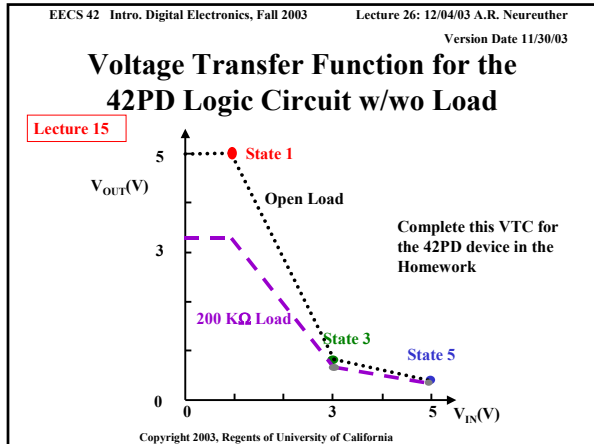
$I_{OUT} (\mu A)$

$V_{THEVENIS} (200K \text{ Load}) = 3.3 V$

$V_{THEVENIS} (Open \text{ Load})$

State 1  
 State 3  
 State 5

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### Lecture 18 CMOS Logic Gate: Example Inputs

A = 0  
B = 1  
C = 1

PMOS A conducts; B and C Open  
Output is High = 0

NMOS B and C conduct; A open  
Logic is Complementary and produces  $F = 0$

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### Lecture 19 Logic Gate Propagation Delay: Initial State

The **initial state** depends on the old (previous) inputs.  
The **equivalent resistance** of the pull-down or pull-up network for the transient phase depends on the new (present) input state.

Example: A=0, B=0, C=0 for a long time.  
These inputs provided a path to  $V_{DD}$  for a long time and the capacitor has precharged up to  $V_{DD} = 5V$ .

$C_{OUT} = 50 \text{ fF}$

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### Lecture 20 Logic Gate Cascade

To avoid large resistance due to many gates in series, logic functions are usually made from cascading two or more 2-4 input blocks.

$B2 = V_{OUT1}$

The four independent input are A1, B1, A2 and C2.

A2 high discharges gate 2 without even waiting for the output of gate 1.

C2 high and A2 low makes gate 2 wait for Gate 1 output

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### Lecture 21 Latch Work Best In Pairs

The first stage operates while the clock is low and inverts and amplifies the arriving signal and charges or discharges  $C_{L1}$ .

The second stage operates while the clock is high and inverts the signal on  $C_{L1}$  to charge or discharge  $C_{L2}$  and downstream logic gate inputs.

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### Lecture 22 Latch Operation: Pipelined

Low High Low High Low High

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### Lecture 22 Latch Timing Diagram

A1 = 0 B1 = 1  
B2 = 1 C2 = 0 1 => 0

Logic level

Clock

$P = 20$  inverter delays

L0\_EXT

G1

L1\_INT

L1\_EXT

G2

L2\_INT

Time (inverter delays)

Latency 32 inverter delays  
Throughput =  $1/(20 \times 345\text{ps}) = 0.145 \text{ GHz}$

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**Lecture 22**

### Latency and Throughput

Latency  $L$  is the delay between the rising edge of the clock on  $L0$  and the data being valid internally in the last latch.

$$L_{LUMPED} = \tau_{L\_EXT} + \tau_{GATE1} + \tau_{GATE2} + \tau_{L\_INT}$$

$$= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 8\tau_{INV}$$

$$L_{PIPELINED} = \tau_{L\_EXT} + \tau_{GATE1} + \tau_{L\_INT} + \tau_{L\_EXT} + \tau_{GATE2} + \tau_{L\_INT}$$

$$= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 12\tau_{INV}$$

Throughput  $T$  is the bits per second through the latches and is the maximum clock frequency.

$$P_{LUMPED} = \tau_{L\_EXT} + \tau_{GATE1} + \tau_{GATE2} + \tau_{L\_INT}$$

$$= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 8\tau_{INV}$$

$$F_{LUMPED} = 1/8(345ps) = 0.36 \text{ GHz}$$

$$P_{PIPELINED} = \tau_{L\_EXT} + \text{MAX}(\tau_{GATE1}, \tau_{GATE2}) + \tau_{L\_INT}$$

$$= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 6\tau_{INV} \quad F_{PIPELINED} = 1/6(345ps) = 0.48 \text{ GHz}$$

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**Lecture 25: on blackboard**

### Limitations of Power Consumption

- The resistive load of NMOS results in D.C. current and hence static power consumption given by the product of current times voltage.
- CMOS avoids this static loss as the pull-up device shuts off the current completely.
- CMOS still suffers a.c. power consumption that is proportional to the switching frequency.
- The energy expended per cycle of in charging and discharging can never be less than  $CV^2$

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### DIODE I-V CHARACTERISTICS AND MODELS

The equation  $I = I_{SAT} (e^{qV/kT} - 1)$  is graphed below for  $V = -15, -10, -5, 0, 5, 10$ .

**Simple "Perfect Rectifier" Model**

If we can ignore the small forward-bias voltage drop of a diode, a simple effective model is the "perfect rectifier," whose I-V characteristic is given below:

The characteristic is described as a "rectifier" – that is, a device that permits current to pass in only one direction. (The hydraulic analog is a "check valve".) Hence the symbol:

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### COOL THINGS A DIODE CAN DO

(Use perfect rectifier model)

"rectified" version of input waveform

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**Lecture 22**

### Physics of Current Flow, Resistance, Resistivity

$E = V/L$   
 $I = V/R$   
 $R = \rho L/A = (1/q \mu N) L/W t = (L/W) / (\mu q N t)$

Carrier mobility  
Carriers per unit volume

But  $q N t$  has the dimensions of charge per unit area and represents the charge per unit area in a film of thickness  $t$  when the film has  $N$  carriers/cm<sup>3</sup> and is  $t$  units thick. Thus we call  $q N t$  the "Q" and

$$R = (L/W) / \mu Q = L/W R_{\square}$$

Where  $R_{\square}$  is the resistance of a "square" of the film. Clearly if  $L$  is four times  $W$ , then  $R = 4 R_{\square}$ .

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### Relation of Current to Physical Parameters

$$I_D = \mu_n C_{ox} \left(\frac{W}{L}\right)_n (V_{GS} - V_T) \cdot V_{OUT-SAT-n}$$

Mobility of carriers  
Oxide thickness  
Excess Gate drive  
Voltage of scattering velocity limit  
Geometrical Layout

$$\mu_n = 500 (cm^2 / Vs) \quad \mu_p = 150 (cm^2 / Vs)$$

$$C_{ox} = \frac{\epsilon_{ox}}{t_{ox}} = \frac{(8.85 \times 10^{-14} F/cm)(3.9)}{6 \times 10^{-7} cm} = 5.75 \times 10^{-7} F/cm^2$$

$$V_{OUT-SAT-n} = E_{Crit} \cdot L = 10^4 (V/cm) \cdot 0.25 \times 10^{-4} cm = 0.25V$$

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